AND / FA

B11901027 王仁軒

NM with Wa Variation

SNM:

Noise margin does not change with Wa

```
Wa = 0.36 \text{ um} Wa = 0.48 \text{ um} Wa = 0.60 \text{ um} 0.794 = 0.794
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RNM:

Noise margin ↓ with Wa ↑

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Wa = 0.36 \text{ um} Wa = 0.48 \text{ um} Wa = 0.60 \text{ um} 0.373 > 0.291 > 0.222
```

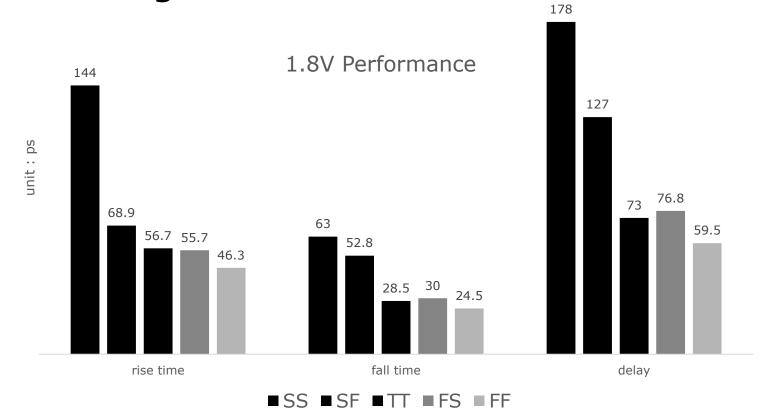

Noise margin ↑ with Wa ↑

AND

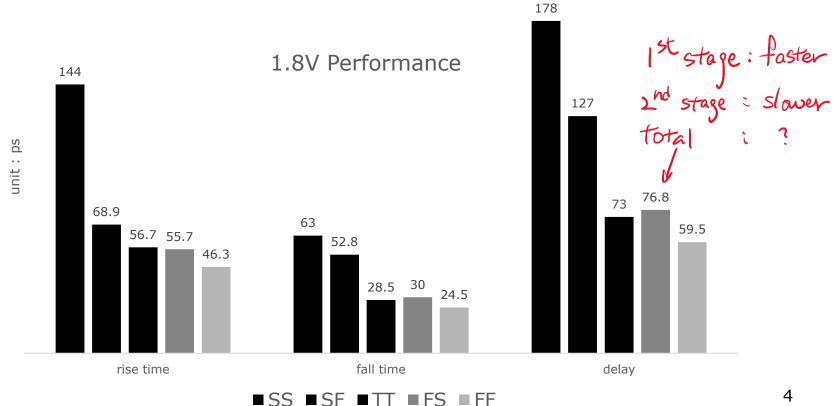
☐ Fastest at FF, slowest at SS

 $\frac{1}{\sqrt{\frac{2}{\sqrt{2}}}} = \frac{1}{\sqrt{\frac{2}{\sqrt{2}}}} = \frac{1}{\sqrt{2}} = \frac{1}{\sqrt{\frac{2}{\sqrt{2}}}} = \frac{1}{\sqrt{\frac{2}{\sqrt{2}}}}} = \frac{1}{\sqrt{\frac{2}{\sqrt{2}}}}} = \frac{1}{$

□ No Sizing -> rise time = 2x fall time

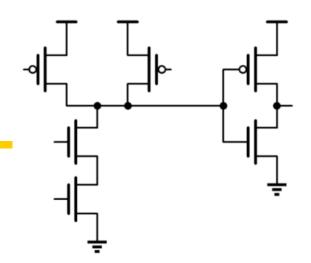


- □ Delay: FS > SF
 - Unbalanced size -> maximum delay + at falling

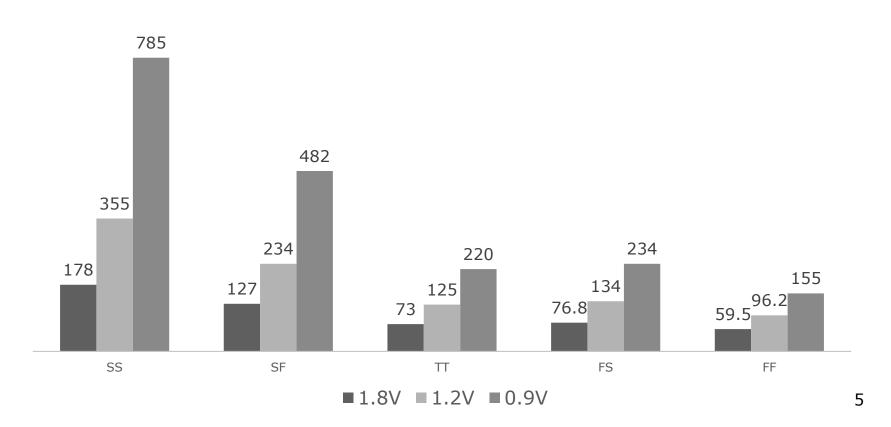


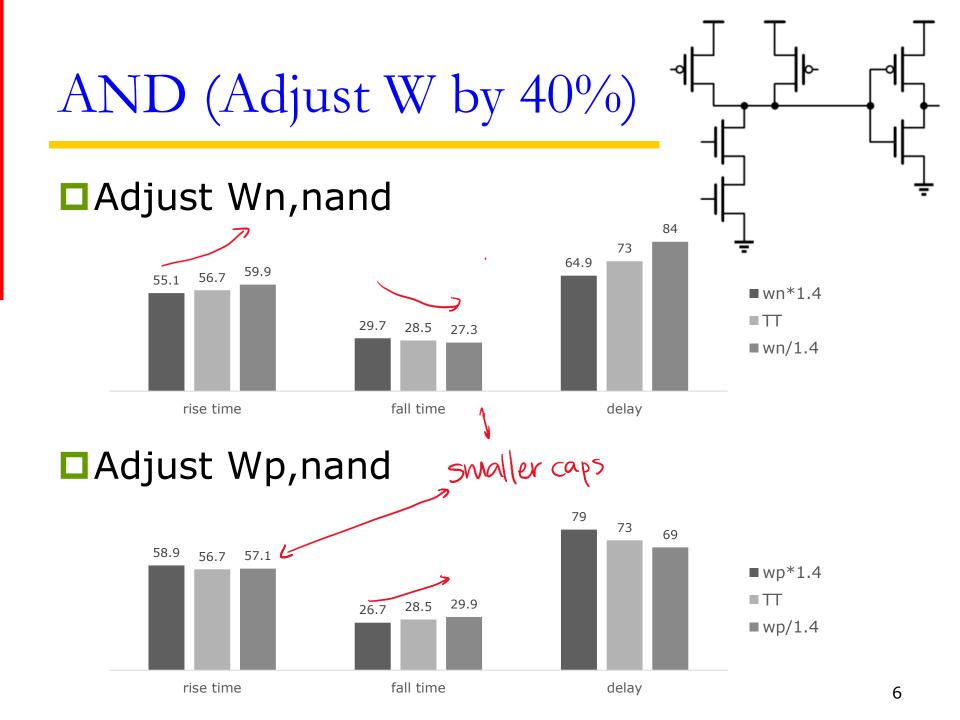
AND

□ High VDD -> Faster



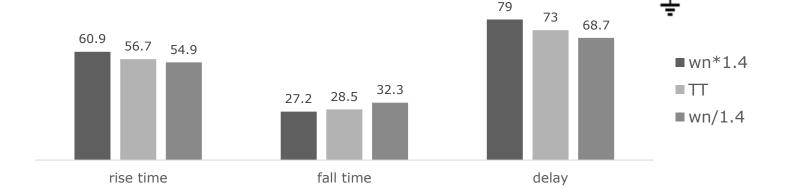
Delay of VDD variation



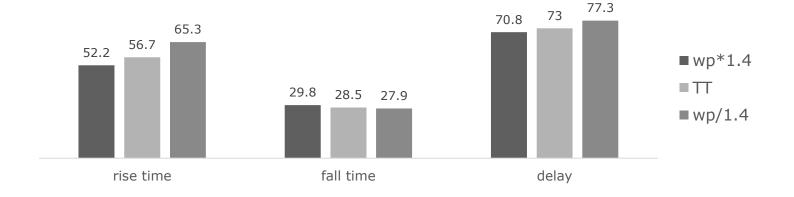


AND (Adjust W by 40%)

□Adjust Wn,inv

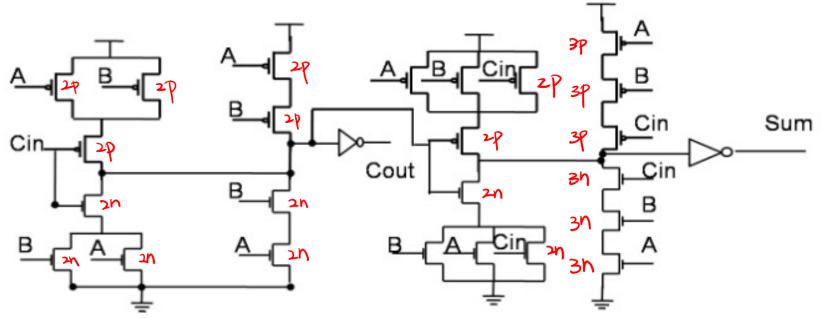


□ Adjust Wp,inv

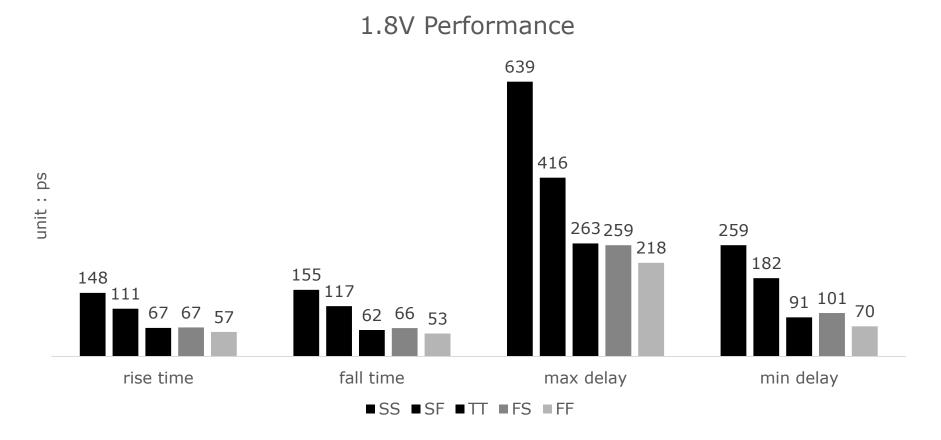


■ Structure

- \blacksquare Cout = MAJ(A , B , Cin)
- Sum = ABC + $(A + B + Cin)\overline{Cout}$
- \blacksquare Wp = 0.75u, Wn = 0.25u

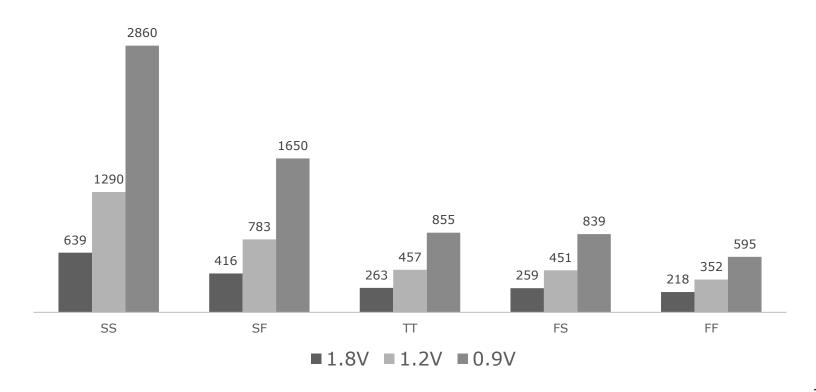


☐ Fastest at FF, slowest at SS



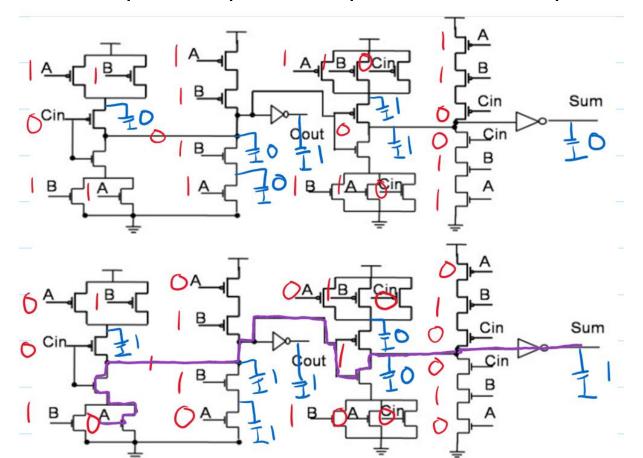
□ High VDD -> Faster

Delay of VDD variation



Critical path

■ A: 1->0 , B: 1 , Cin: 0, Cout: 1->0, Sum: 0->1



- Critical path
 - A: 1->0 , B: 1 , Cin: 0, Cout: 1->0, Sum: 0->1
 - Delay can be estimated by Elmore RC model
 - Longer path -> larger effective capacitance

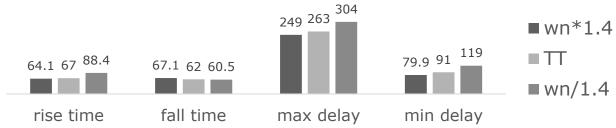
$$t_{pd} \approx \sum_{\text{nodes } i} R_{i-to-source} C_{i}$$

$$= R_{1}C_{1} + (R_{1} + R_{2})C_{2} + \dots + (R_{1} + R_{2} + \dots + R_{N})C_{N}$$

28T Full Adder (Adjsut W by 40%)

Adjust Wn (excluding inverters)

Wn,nand



- □Adjust Wp (excluding inverters)
 - Shorter delay when reducing size of Wp
 - Max/Min delay happens at Sum : 0 -> 1

